

Notice of References Cited

Application Control No.

09 628 116

Applicant(s): Patent Under

Reexamination

SOBOLEW, SK, ET AL

Examiner

Timothy J. Moran

Art Unit

2878

Page 1 of 1

U.S. PATENT DOCUMENTS

★		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

★		Include as applicable: Author Title Date Publisher Edition or Volume Pertinent Pages				
	U	Ghis et al. "Electrical picosecond measurements of the photoresponse in YBa ₂ Cu ₃ O _{7-x} " Appl. Phys. Lett. 63: 551 (1993)				
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